TE42 V2

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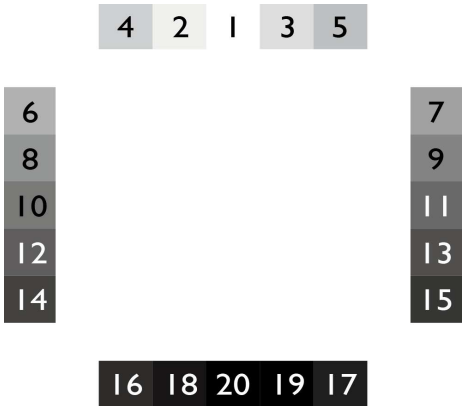
Acceptance Protocol

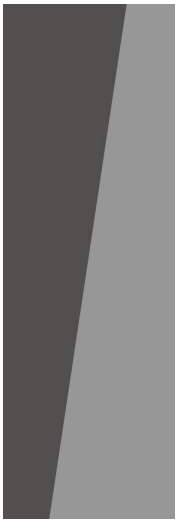
SN:	EXAMPLE VALUES
Order Confirmation:	
Date:	
Operator:	

OECF



Patch			
Step	Measured	Reference	Deviation
1		0,06	
2		0,12	
3		0,19	
4		0,25	
5		0,32	
6		0,40	
7		0,48	
8		0,57	
9		0,66	
10		0,76	
11		0,86	
12		0,98	
13		1,11	
14		1,25	
15		1,40	
16		1,58	
17		1,79	
18		2,04	
19		2,35	
20		3,00	
Background		0,80	

RESOLUTION / SLANTED EDGES



	Measured density	Calculated reflectance	Modulation	Contrast Ratio
low contrast	1,10	0,08	53%	3
	0,59	0,26		
high contrast	1,40	0,04	86%	13
	0,29	0,51		

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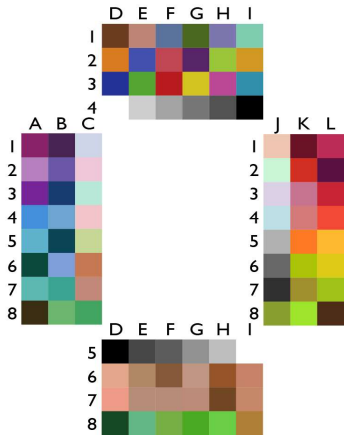
COLOR



	L	a	b
A1	32	55	-22
A2	62	32	-26
A3	32	56	-55
A4	50	-15	-39
A5	61	-24	-19
A6	18	-21	-4
A7	64	-35	-10
A8	15	0	8

	L	a	b
B1	16	27	-29
B2	41	28	-45
B3	22	1	-33
B4	58	-14	-25
B5	17	-14	-16
B6	60	-2	-30
B7	52	-43	-11
B8	62	-37	19

	L	a	b
C1	81	-2	-6
C2	80	11	-1
C3	85	-16	-3
C4	80	14	7
C5	82	-14	26
C6	57	27	34
C7	59	21	16
C8	53	-47	13

	L	a	b
D1	24	22	29
D2	61	35	70
D3	27	21	-51
D4	93	-1	-3
D5	5	1	-2
D6	72	20	23
D7	70	29	24
D8	16	-20	5

	L	a	b
E1	58	20	17
E2	35	14	-46
E3	54	-47	49
E4	76	-1	-2
E5	24	0	-2
E6	58	12	24
E7	59	15	16
E8	65	-37	5

	L	a	b
F1	44	-3	-23
F2	43	53	18
F3	38	59	33
F4	60	0	-2
F5	34	0	-1
F6	38	15	28
F7	59	15	15
F8	60	-31	48

	L	a	b
G1	34	-17	30
G2	19	42	-40
G3	74	3	76
G4	43	-1	-2
G5	54	-1	-2
G6	62	15	15
G7	59	18	17
G8	56	-47	51

	L	a	b
H1	53	10	-29
H2	71	-23	68
H3	46	54	-25
H4	29	-1	-2
H5	71	-1	-2
H6	38	27	43
H7	28	20	31
H8	63	-52	54

	L	a	b
I1	74	-32	-1
I2	68	17	73
I3	46	-24	-27
I4	5	1	-2
I5	94	-1	-2
I6	59	24	23
I7	61	22	25
I8	55	15	51

	L	a	b
J1	79	12	15
J2	88	-16	5
J3	82	2	-6
J4	83	-11	-6
J5	66	0	-2
J6	38	0	-2
J7	13	-1	-2
J8	59	-17	57

	L	a	b
K1	18	35	7
K2	46	63	43
K3	57	32	4
K4	61	35	16
K5	61	42	67
K6	75	-9	73
K7	53	1	53
K8	76	-27	74

	L	a	b
L1	38	64	9
L2	16	32	-12
L3	40	63	30
L4	49	62	46
L5	74	15	78
L6	78	3	78
L7	74	-16	73
L8	16	12	17

TE42V2AP260629

All values in this certificate measured with X-Rite eXact.
https://www.image-engineering.de/content/products/charts/IE_reference_data_accuracy.pdf